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EVENT CALENDAR

North American FIB & DualBeam™ UserClub
Oct. 7 - Oct. 9
Hillsboro, Oregon

SEMICON Europa
Oct. 7 - Oct. 9
Stuttgart, Germany

ASM Materials Science & Technology
Oct. 7 & Oct. 8
Pittsburgh, PA

9th Asia-Pacific Microscopy Conference
Nov. 2 - Nov. 7
Jeju Island, Korea

ISTFA
Nov. 4 - Nov. 5
Portland, OR

Materials Research Society
Dec. 2 - Dec. 4
Boston, MA

> 2008 Event Calendar

QUICK LINKS

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